
**Information technology — Automatic
identification and data capture
techniques — Direct Part Mark (DPM)
Quality Guideline**

*Technologies de l'information — Techniques automatiques
d'identification et de capture de données — Ligne directrice de
qualité du marquage direct sur pièce (DPM)*

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Contents

Page

Foreword	v
Introduction	vi
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Symbols and abbreviated terms	2
5 Overview of methodology	2
5.1 Process differences from ISO/IEC 15415	2
5.2 Lighting	3
5.3 Tilted coaxial lighting and camera position (TCL)	3
6 Obtaining the image	4
6.1 Camera position and symbol orientation	4
6.1.1 Symbol placement	4
6.1.2 Camera position in a 90 ° camera angle set up	5
6.1.3 TCL setup	5
6.2 Lighting environments	5
6.2.1 General	5
6.2.2 Perpendicular coaxial (90)	5
6.2.3 Diffuse off-axis (D)	5
6.2.4 Four direction (angle Q)	5
6.2.5 Two direction (angle T)	5
6.2.6 One direction (angle S)	6
6.2.7 TCL Setup	6
6.3 Image focus	6
6.4 Depth of field	6
6.5 System response adjustment and reflectance calibration	6
7 Verifying a symbol	7
7.1 Initial image reflectance	7
7.1.1 General	7
7.1.2 Initialize aperture size	7
7.1.3 Create initial histogram	7
7.1.4 Compute mean	7
7.1.5 Optimize image	7
7.2 Obtaining the test image	7
7.2.1 Matrix symbologies	7
7.2.2 Binarize image	7
7.3 Apply Reference Decode Algorithm	8
7.3.1 General	8
7.3.2 Repeat if necessary	8
7.3.3 Continue until end	8
7.4 Final image adjustment	8
7.4.1 General	8
7.4.2 Determine grid-point reflectance with two apertures	8
7.4.3 Create a grid-point histogram	8
7.4.4 Measure mean light (M_L)	8
7.4.5 Record parameters	8
7.4.6 Create binarized images for the symbology reference decode	9
7.4.7 Decode	9
8 Determine contrast parameters	9
8.1 Initialize aperture size	9
8.2 Calculate cell contrast (CC)	9

8.3	Calculate cell module modulation (CMOD).....	9
8.4	Calculate minimum reflectance (R_{target}).....	9
9	Grading	10
9.1	Cell contrast (CC).....	10
9.2	Minimum reflectance (R_{target}).....	10
9.3	Cell modulation (CM).....	11
9.4	Fixed pattern damage (FPD).....	11
9.5	Final grade.....	12
10	Communicating grade requirements and results	12
10.1	General.....	12
10.2	Communication of application requirements.....	12
10.3	Communicating from verifier to application.....	12
10.4	Communicating the use of a proprietary decode.....	12
Annex A	(normative) Threshold determination method	14
Annex B	(informative) Evaluation of image at virtual 90° camera position from real tilted camera position	18
Annex C	(normative) Continuous grading for ISO/IEC 15415 parameters	22
Annex D	(normative) Dot connecting algorithm	27
Annex E	(informative) Communicating the grade	29
Annex F	(informative) Cross reference to ISO/IEC 15415	32
Bibliography		33

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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO and IEC shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents) or the IEC list of patent declarations received (see <https://patents.iec.ch>).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Joint Technical Committee ISO/TC JTC 1, *Information Technology*, Subcommittee SC 31, *Automatic identification and data capture techniques*.

This first edition cancels and replaces ISO/IEC TR 29158:2011, which has been technically revised.

The main changes compared to the previous edition are as follows:

- inclusion of continuous grading;
- expanded grading levels for minimum reflectance (R_{target});
- inclusion of a tilted lighting and camera position;
- reorganized proposed lighting options.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Direct Part Marking (DPM) is a technology whereby, generally, an item is physically altered to produce two different surface conditions. This alteration can be accomplished by various means including, but not limited to, dot peen, laser mark, ink jetting, and electro-chemical etch. The area of the alteration is called "the mark." The area that includes the mark and background as a whole, when containing a pattern defined by a bar code symbology specification, is called "a symbol."

When light illuminates a symbol, it reflects differently depending on whether it impinges on the background of the part or on the physical alteration. In most non-DPM bar code scanning environments, light is reflected off a smooth surface that has been coloured to produce two different diffuse reflected states. The DPM environment generally does not fit this model because the two different reflected states depend on at least one of the states having material oriented to the lighting such that the angle of incidence is equal to the angle of reflection. Sometimes the material so oriented produces a specular (mirror like) reflectance that results in a signal that is orders of magnitude greater than the signal from diffuse reflectance.

In addition, from the scanner point-of-view, some marking and printing methods generate dots and are not capable of producing smooth lines. This is important for symbologies such as Data Matrix, which is specified to contain smooth continuous lines, but can be marked with disconnected dots in DPM applications.

Current specifications for matrix symbologies and two-dimensional print quality are not exactly suited to reading situations that have either specular reflection or unconnected dots or both. Additionally, symbologies specified to consist of smooth continuous lines may appear with unconnected dots. This is intended to act as a bridge between the existing specifications and the DPM environment in order to provide a standardized image-based measurement method for DPM that is predictive of scanner performance.

As with all symbology and quality standards, it is the responsibility of the application to define the appropriate parameters of this guideline for use in conjunction with a particular application.

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